

L Number	Hits	Search Text	DB	Time stamp
-	5874	((Transition near2 electron near2 (microscope or microscopy)) or TEM) and (Beam or probe or arm or (micro near2 hand) or tip or needle)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 19:27
-	9187	250/310 250/311 250/492.2 250/307	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 13:13
-	219	((((Transition near2 electron near2 (microscope or microscopy)) or TEM) and (Beam or probe or arm or (micro near2 hand) or tip or needle)) and (250/310 250/311 250/492.2 250/307)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 13:14
-	3868	((Transition near2 electron near2 (microscope or microscopy)) or TEM) and (Beam or probe or arm or (micro near2 hand) or tip or needle) and (sample or workpiece or specimen)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 19:27
-	205	((((Transition near2 electron near2 (microscope or microscopy)) or TEM) and (Beam or probe or arm or (micro near2 hand) or tip or needle) and (sample or workpiece or specimen)) and (250/310 250/311 250/492.2 250/307)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 16:26
-	2	4939364.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 16:29
-	2	5093572.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 16:31
-	2	5171717.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 16:32
-	2	5270552.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 17:37
-	2	5852298.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 17:53
-	0	"method and apparatus for preparing samples".ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 18:00
-	41	method near 6300631.PN. apparatus near3 preparing adj samples.ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 18:00

-	0	"method and apparatus for preparing sample".ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 18:00
-	6	method adj apparatus adj preparing adj sample.ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 18:02
-	5	method adj device adj preparing adj sample.ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 18:04
-	726455	Hitachi.as.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 18:06
-	270	(Hitachi.as. and @ad>1995) and ((Transition near2 electron near2 (microscope or microscopy)) or TEM)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 18:10
-	0	(Hitachi.as. and @ad>1995) and ((Transition near2 electron near2 (microscope or microscopy)) or TEM) and @ad=1997	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 18:11
-	270	(Hitachi.as. and @ad>1995) and ((Transition near2 electron near2 (microscope or microscopy)) or TEM) and @ad>1996	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 18:11
-	18631	((Transmission adj electron adj (microscope or microscopy)) or TEM)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 19:34
-	2	5270552.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 15:31
-	686273	Hitachi.as. and @ad>1995	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 15:43
-	5	(Hitachi.as. and @ad>1995) and (MANIPULATOR and PROBE and DEVICE).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 15:44
-	210039	(Beam or probe or arm or (micro near2 hand) or tip or needle) and (vacuum or vaccum)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/19 11:09
-	7905	250/310 250/311 250/307 250/492.1 250/440.11	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/19 11:09

-	2180	(250/310 250/311 250/307 250/492.1 250/440.11) and ((Beam or probe or arm or (micro near2 hand) or tip or needle) and (vacuum or vaccum))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/19 11:09
-	49461	(Beam or probe or arm or (micro near2 hand) or tip or needle) with (vacuum or vaccum)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/19 11:12
-	1107	((Beam or probe or arm or (micro near2 hand) or tip or needle) with (vacuum or vaccum)) and (250/310 250/311 250/307 250/492.1 250/440.11)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/19 11:11
-	7741	((Beam or probe or arm or (micro near2 hand) or tip or needle) with (vacuum or vaccum)) and (((Scanning adj electron adj microscope) or (scanning near3 microscope) or SEM) or (ion adj beam))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/19 11:17
-	742	((Beam or probe or arm or (micro near2 hand) or tip or needle) with (vacuum or vaccum)) and (((Scanning adj electron adj microscope) or (scanning near3 microscope) or SEM) or (ion adj beam))) and (250/310 250/311 250/307 250/492.1 250/440.11)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/19 11:16
-	4540	((Beam or probe or arm or (micro near2 hand) or tip or needle) near5 (vacuum or vaccum)) and (((Scanning adj electron adj microscope) or (scanning near3 microscope) or SEM) or (ion adj beam))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/19 11:19
-	451	((Beam or probe or arm or (micro near2 hand) or tip or needle) near5 (vacuum or vaccum)) and (((Scanning adj electron adj microscope) or (scanning near3 microscope) or SEM) or (ion adj beam))) and (250/310 250/311 250/307 250/492.1 250/440.11)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/19 11:19
-	2737	((Beam or probe or arm or (micro near2 hand) or tip or needle) near3 (vacuum or vaccum)) and (((Scanning adj electron adj microscope) or (scanning near3 microscope) or SEM) or (ion adj beam))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/19 11:21
-	304	((Beam or probe or arm or (micro near2 hand) or tip or needle) near3 (vacuum or vaccum)) and (((Scanning adj electron adj microscope) or (scanning near3 microscope) or SEM) or (ion adj beam))) and (250/310 250/311 250/307 250/492.1 250/440.11)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/19 11:22